Se	Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
09/661,806	HASEGAWA ET AL.
Examiner	Art Unit
Sunray Chang	2121

SEARCHED					
Class	Subclass	Date	Examiner		
703	2	8/7/2005	sc		
345	434,441	8/7/2005	sc		
345	419-421	8/7/2005	sc		
345	431,426	8/7/2005	sc		
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INTERFERENCE SEARCHED				
Subclass	Date	Examiner		
2	8/7/2005	sc		
419-441	8/7/2005	sc		
	Subclass 2	Subclass Date 2 8/7/2005		

SEARCH NO (INCLUDING SEARCH		)
	DATE	EXMR
EAST (USPAT, US_PGPUB, JPO, EPO, DERWENT, IBM_TDB)	8/7/2005	sc